## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10517917	MARTENS ET AL.
Examiner	Art Unit
Heyi, Henok G	2609

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Searched three different classes by combining with text search. I also used the international search report to reject all claims.	07/12/07	Henok Heyi
369/94, 275.4, 288 (text search only - see the search history printout)	07/12/07	Henok Heyi
Updated search and consulted with Primary Wayne Young.	07/03/2008	Henok Heyi
Updated search.	04/10/2009	Henok Heyi

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/HENOK G HEYI/ Examiner.Art Unit 2627	

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